

PRODUCT DATA SHEET

LIGHTNING PROTECTION AND EARTHING SYSTEM COMPONENTS

Code: 62 21 830 (copper clamp) / 62 21 831 (tin plated copper clamp)

Description: Conductor connection clamp

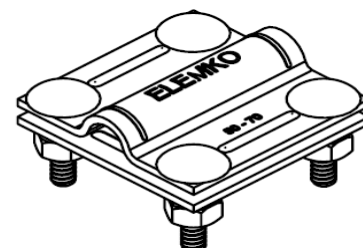
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Application

Clamp, for connecting solid round or stranded conductor to tape conductor. Used in air termination system, down conductor system, earthing system.

Classification

- Heavy duty (H – 100 kA)⁽¹⁾
 - General use⁽¹⁾
 - Intended to withstand a static mechanical load⁽¹⁾
 - Non-permanent connection⁽¹⁾
 - Short circuit withstand capability 10 kA rms for 3s
- ⁽¹⁾ As per IEC EN 62561



Technical characteristics

| | |
|--------------|---|
| Material | Copper (Cu) and/or tin plated copper (Cu/eSn) |
| Description | Is consisted of two plates with dimensions 50x50 mm. |
| Bolts / nuts | M6x25 mm, V2A stainless steel carriage bolts M6 V2A stainless steel nuts |

Installation instructions

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|--|--|
| Conductor's dimensions | Ø8–10 mm (50–70 mm ²) |
| Tape's dimensions | Up to 30 mm width and 5 mm thickness |
| Connection arrangements | Cross (B1) Parallel (B2) |
| Installation | Above ground, buried in ground, embedded in concrete |
| Can be connected above ground with | Cu, Cu/eSn, SSt (Stainless Steel), St/eCu, St/tZn* |
| Can be connected buried in ground with | Cu, Cu/eSn, SSt (Stainless Steel), St/eCu |
| Can be connected in concrete with | Cu, Cu/eSn, SSt (Stainless Steel), St/eCu, St/tZn |
| Tightening torque | 9 Nm |

Testing

The component has successfully passed the testing requirements of standard IEC EN 62561-1 "Lightning protection system components (LPSC) – Part 1 : Requirements for connection components".

Test report No **30751** by accredited laboratory as per ISO 17025

The component has successfully passed short circuit withstand capability tests.

Test report No **319/2014/EMI**

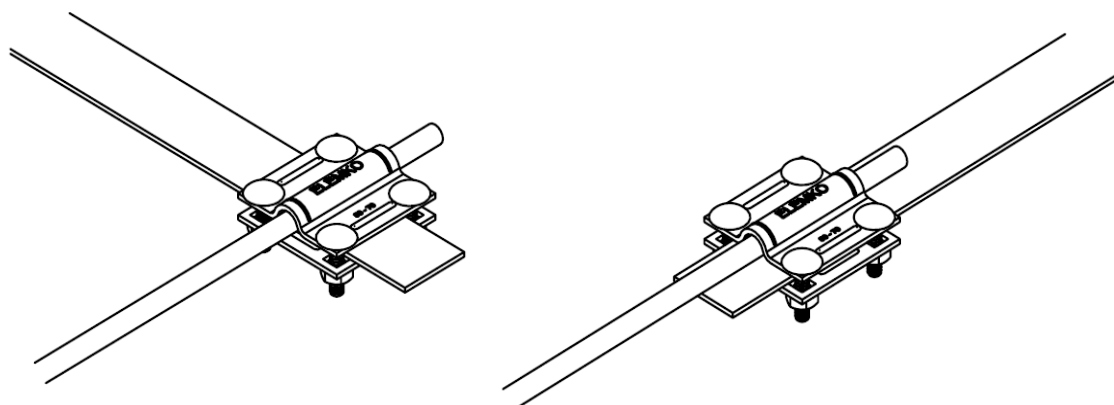
Manufacturing Quality Control

Manufacturing quality control according standard ISO 9001

Country of Origin

Greece

Unit: piece / Package: 25 pieces



*Only for tin plated copper clamp and not simultaneously with Cu, St/eCu.

We reserve the right to introduce changes in the component due to technical evolution.